

<b>Notice of References Cited</b>	Application/Control No. 09/942,678	Applicant(s)/Patent Under Reexamination YAMAGUCHI ET AL.	
	Examiner Nikolas J. Uhlir	Art Unit 1773	Page 1 of 1

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	C	US-4,661,216	04-1987	Anderson et al.	205/260
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	L	US-			
	M	US-			

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#### NON-PATENT DOCUMENTS

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.